FEATURES

■ Fast access time : 55ns
 ■ Low power consumption:
 Operating current : 30mA (TYP.)
 Standby current : 6µA (TYP.) LL-version

■ Single 2.7V ~ 5.5V power supply

■ All inputs and outputs TTL compatible

Fully static operationTri-state output

JANUARY 2008

Data retention voltage: 1.5V (MIN.)Lead free and green package available

■ Package: 44-pin 400 mil TSOP-II

48-ball 6mm x 8mm TFBGA

GENERAL DESCRIPTION

The AS6C8008 is a 8,388,608-bit low power CMOS static random access memory organized as 1,048,576 words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

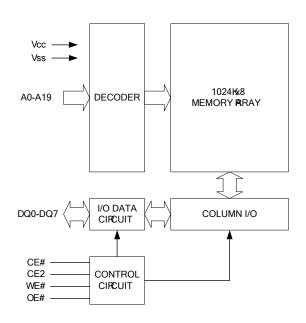
The AS6C8008 is well designed for very low power system applications, and particularly well suited for battery back-up nonvolatile memory application.

The AS6C8008 operates from a single power supply of $2.7V \sim 5.5V$ and all inputs and outputs are fully TTL compatible

PRODUCT FAMILY

Product	Operating	Vcc Range	Speed	Power D	issipation
Family	Temperature	v cc r ange	Opeed	Standby(IsB1,TYP.)	Operating(Icc,TYP.)
AS6C8008(I)	-40 ~ 85℃	2.7 ~ 5.5V	55ns	6µA(LL)	30mA

FUNCTIONAL BLOCK DIAGRAM

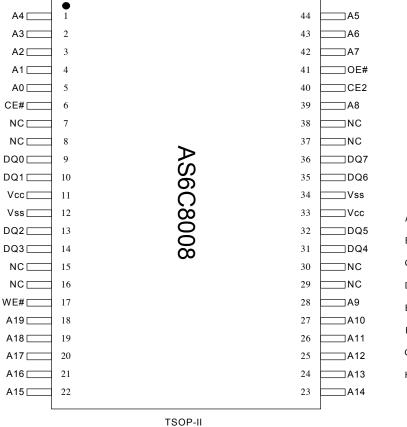


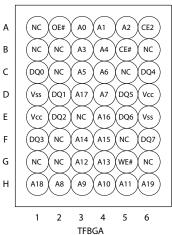
PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0 - A19	Address Inputs
DQ0 – DQ7	Data Inputs/Outputs
CE#, CE2	Chip Enable Inputs
WE#	Write Enable Input
OE#	Output Enable Input
Vcc	Power Supply
Vss	Ground
NC	No Connection



PIN CONFIGURATION





ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	RATING	UNIT
Voltage on Vcc relative to Vss	V _{T1}	-0.5 to 6.5	V
Voltage on any other pin relative to Vss	V _{T2}	-0.5 to Vcc+0.5	V
Operating Temperature	TA	-40 to 85(I grade)	$^{\circ}$ C
Storage Temperature	Тѕтс	-65 to 150	$^{\circ}\!\mathbb{C}$
Power Dissipation	PD	1	W
DC Output Current	Іоит	50	mA
Soldering Temperature (under 10 sec)	Tsolder	260	$^{\circ}$ C

^{*}Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	CE#	CE2	OE#	WE#	I/O OPERATION	S UPPLY CUR RENT	
Standby	Н	Х	Х	Х	High-Z	I _{SB1}	
Staridby	Х	L	Х	Х	High-Z	I _{SB1}	
Output Disable	L	Н	Н	Н	High-Z	lcc,lcc1	
Read	L	Н	L	Н	Dout	lcc,lcc1	
Write	L	Н	Х	L	Din	lcc,lcc1	

Note: H = V_{IH}, L = V_{IL}, X = Don't care.

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION MIN		N. TYP.	*4	MAX.	UNIT
Supply Voltage	Vcc			2.7	3.0	5.5	V
Input High Voltage	V _{IH} ^{*1}			2.4	-	Vcc+0.3	V
Input Low Voltage	V _{IL} *2			- 0.2	-	0.6	V
Input Leakage Current	ILI	$Vcc \ge Vin \ge Vss$		- 1	-	1	μΑ
Output Leakage Current	ILO	Vcc ≧ Vouт ≧ Vss Output Disabled		- 1	-	1	μA
Output High Voltage	Vон	I _{OH} = -1mA		2.4	2.7	-	V
Output Low Voltage	Vol	I _{OL} = 2mA		-	-	0.4	V
Average Operating	Icc	Cycle time = Min. CE# = V _{IL} and CE2 = V _{IH} I _{I/O} = 0mA Other pins at V _{IL} or V _{IH}	- 55	-	30	60	mA
Power supply Current	lcc1	Cycle time = 1μ s CE# \leq 0.2V and CE2 \geq V _{CC} -0.2V I _{I/O} = 0mA Other pins at 0.2V or V _{CC} -0.2V		-	4	12	mA
Standby Power Supply Current	I _{SB1}	CE# \ge Vcc-0.2V or CE2 \le 0.2V Other pins at 0.2V or Vcc-0.2V		-	6	50	μΑ



Notes:

- 1. ViH(max) = Vcc + 3.0V for pulse width less than 10ns.
- 2. VIL(min) = VSS 3.0V for pulse width less than 10ns.
- 3. Over/Undershoot specifications are characterized, not 100% tested.
- 4. Typical values are included for reference only and are not guaranteed or tested. Typical valued are measured at Vcc = Vcc(TYP.) and Ta = 25° C

CAPACITANCE $(T_A = 25?, f = 1.0MHz)$

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	6	pF
Input/Output Capacitance	CI/O	-	8	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Input Pulse Levels	0.2V to V _{CC} - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	$C_L = 30pF + 1TTL$, $I_{OH}/I_{OL} = -1mA/2mA$

AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

PARAMETER	SYM.	AS6C80	08-55	UNIT
		MIN.	MAX.	
Read Cycle Time	trc	55	-	ns
Address Access Time	taa	-	55	ns
Chip Enable Access Time	t ace	-	55	ns
Output Enable Access Time	toe	-	30	ns
Chip Enable to Output in Low-Z	tcLz*	10	-	ns
Output Enable to Output in Low-Z	tolz*	5	-	ns
Chip Disable to Output in High-Z	tcHz*	-	20	ns
Output Disable to Output in High-Z	tonz*	-	20	ns
Output Hold from Address Change	tон	10	-	ns

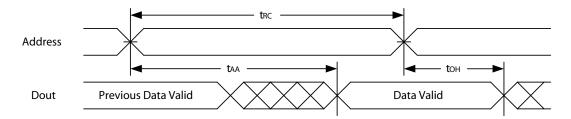
(2) WRITE CYCLE

PARAMETER	SYM.	AS6C80	AS6C8008-55	
		MIN.	MAX.	
Write Cycle Time	twc	55	-	ns
Address Valid to End of Write	taw	50	-	ns
Chip Enable to End of Write	tcw	50	-	ns
Address Set-up Time	tas	0	-	ns
Write Pulse Width	twp	45	-	ns
Write Recovery Time	twr	0	-	ns
Data to Write Time Overlap	tow	25	-	ns
Data Hold from End of Write Time	tон	0	-	ns
Output Active from End of Write	tow*	5	-	ns
Write to Output in High-Z	twnz*	-	20	ns

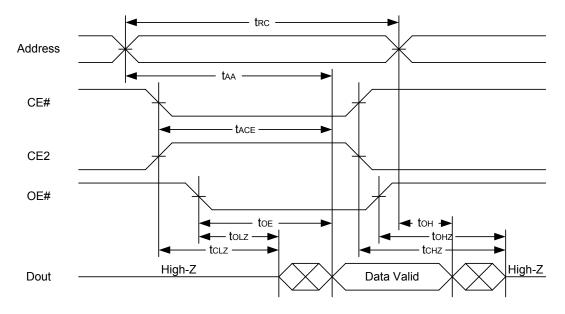
^{*}These parameters are guaranteed by device characterization, but not production tested.

TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)



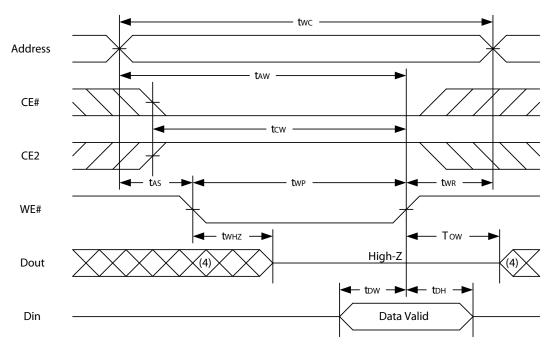
READ CYCLE 2 (CE# and CE2 and OE# Controlled) (1,3,4,5)



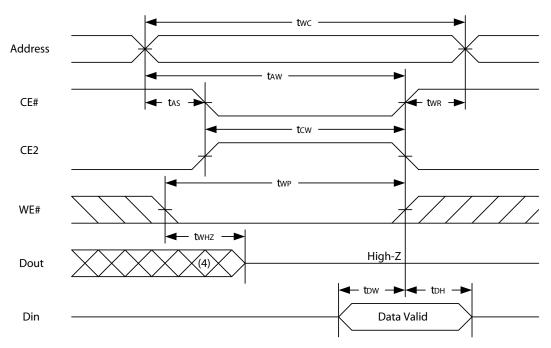
Notes:

- 1.WE# is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low., CE2 = high.
- 3.Address must be valid prior to or coincident with CE# = low, CE2 = high; otherwise tAA is the limiting parameter.
- 4.tclz, tolz, tchz and tohz are specified with CL = 5pF. Transition is measured ±500mV from steady state.
- 5.At any given temperature and voltage condition, t_{CHZ} is less than t_{CLZ} , t_{OHZ} is less than t_{CLZ}

WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



WRITE CYCLE 2 (CE# and CE2 Controlled) (1,2,5,6)



Notes:

- 1.WE#, CE# must be high or CE2 must be low during all address transitions.
- 2.A write occurs during the overlap of a low CE#, high CE2, low WE#.
- 3.During a WE#controlled write cycle with OE# low, twp must be greater than twHz + tpw to allow the drivers to turn off and data to be placed on the bus.
- 4.During this period, I/O pins are in the output state, and input signals must not be applied.
- 5.If the CE#low transition and CE2 high transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
- 6.tow and twHz are specified with C_L = 5pF. Transition is measured $\pm 500mV$ from steady state.

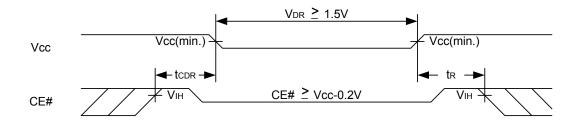
DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX. U	NIT
Vcc for Data Retention	V _{DR}	CE# ≥ V _{CC} - 0.2V or CE2 ≤ 0.2V	1.5	-	5.5	V
Data Retention Current	ldr	Vcc = 1.5V CE# ≥ Vcc - 0.2V or CE2 ≤ 0.2V Other pins at 0.2V or Vcc - 0.2V	-	4	50	μA
Chip Disable to Data Retention Time	tcdr	See Data Retention Waveforms (below)	0	_	-	ns
Recovery Time	t R		t RC∗	-	-	ns

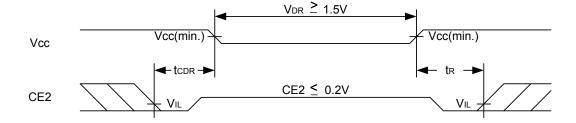
tRC∗ = Read Cycle Time

DATA RETENTION WAVEFORM

Low Vcc Data Retention Waveform (1) (CE# controlled)



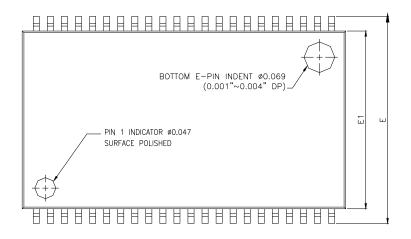
Low Vcc Data Retention Waveform (2) (CE2 controlled)

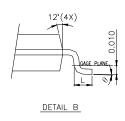


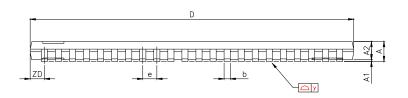


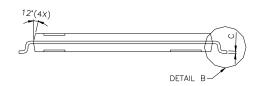
PACKAGE OUTLINE DIMENSION

44-pin 400mil TSOP-II Package Outline Dimension





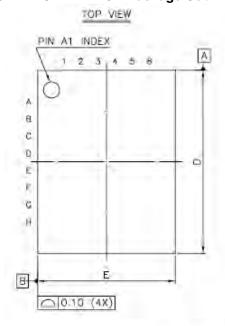


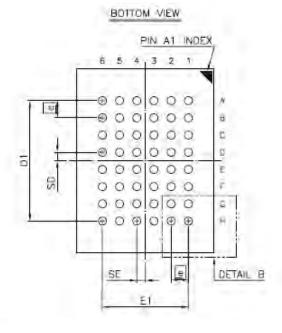


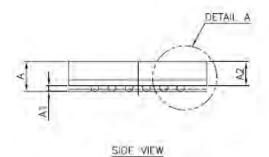
SYMBOLS	DIMENSI	ONS IN MILL	METERS	DIMENSIONS IN MILS			
STWIBULS	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	-	-	1.20	-	-	47.2	
A1	0.05	0.10	0.15	2.0	3.9	5.9	
A2	0.95	1.00	1.05	37.4	39.4	41.3	
b	0.30	-	0.45	11.8	-	17.7	
С	0.12	-	0.21	4.7	-	8.3	
D	18.212	18.415	18.618	717	725	733	
E	11.506	11.760	12.014	453	463	473	
E1	9.957	10.160	10.363	392	400	408	
е	-	0.800	-	-	31.5	-	
L	0.40	0.50	0.60	15.7	19.7	23.6	
ZD	-	0.805	-	-	31.7	-	
У	-	-	0.076	-	-	3	
θ	0°	3°	6°	0°	3°	6°	

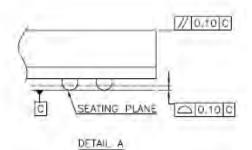


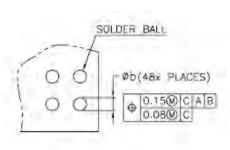
48-ball 6mm × 8mm TFBGA Package Outline Dimension











SYM.	D	MENSIO (mm)	N	DIMENSION (inch)			
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	-	-	1.40	=	-	0.055	
Al	0.20	0.25	0.30	0.008	0.010	0.012	
A2	-	-	1.05	-	-	0.041	
b	0.30	0.35	0.40	0.012	0.014	0.016	
D .	7.95	8.00	8.05	0.313	0.315	0.317	
DI	5	5.25 BSC			207 BS	SC.	
E	5.95	6.00	5.05	0.234	0.236	0.238	
E†	3	.75 BS0	0	. 0	148 BS	SC.	
SE	0	375 TY	P	8	015 TY	p	
SD	0.375 TYP			8.015 TYP			
le -	0	.75 BS0	0	.0	.030 BS	SC.	

NOTE

CONTROLLING DIMENSION : MILLIMETER:
 REFERENCE DOCUMENT : JEDEC MD-207

DETAIL B



ORDERING INFORMATION

Alliance	Organization	VCC Range	Package	Operating Temp	Speed ns
AS6C8008-55ZIN	1024K x 8	2.7 - 5.5V	44pin TSOP II	Industrial ~ -40 C - 85 C	55
AS6C8008-55BIN	1024K x 8	2.7 - 5.5V	48ball TFBGA	Industrial ~ -40 C - 85 C	55

PART NUMBERING SYSTEM

AS6C	8008	-55	Х	Х	N
	Device Number		Package Option	Temperature Range	N = Lead Free
low power S RAM prefix	380 =8M 08 = x8	Access Time	Z - 44pin TSOP B = 48ball TFBGA	I = Industrial (-40 to + 85 C)	RoHS compliant part





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